



ISO9001:2015  
ISO14001:2015  
OHSAS18001:2007

质量认证  
环境认证  
健康认证

技术文件 Technical Data Sheet

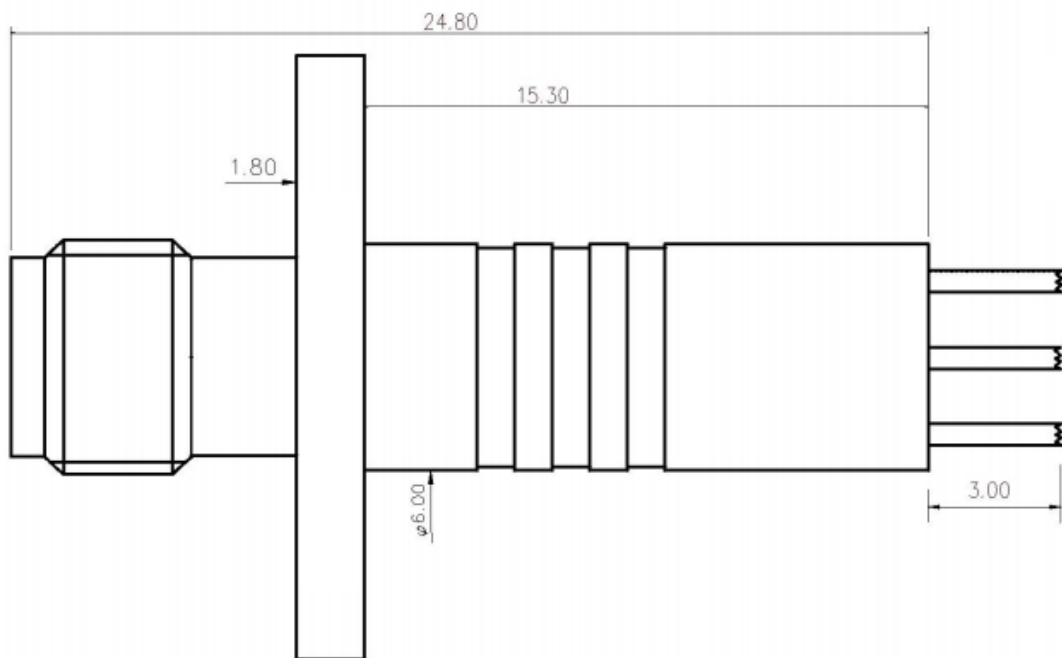
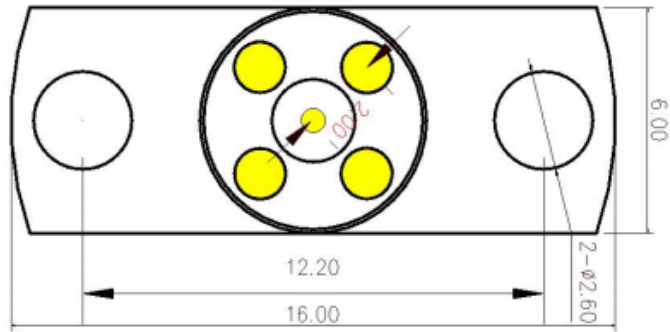
文档编号 DN: XQY002-1700158-E

## XQY-SMAK-TT115Z

### 精密测试探针

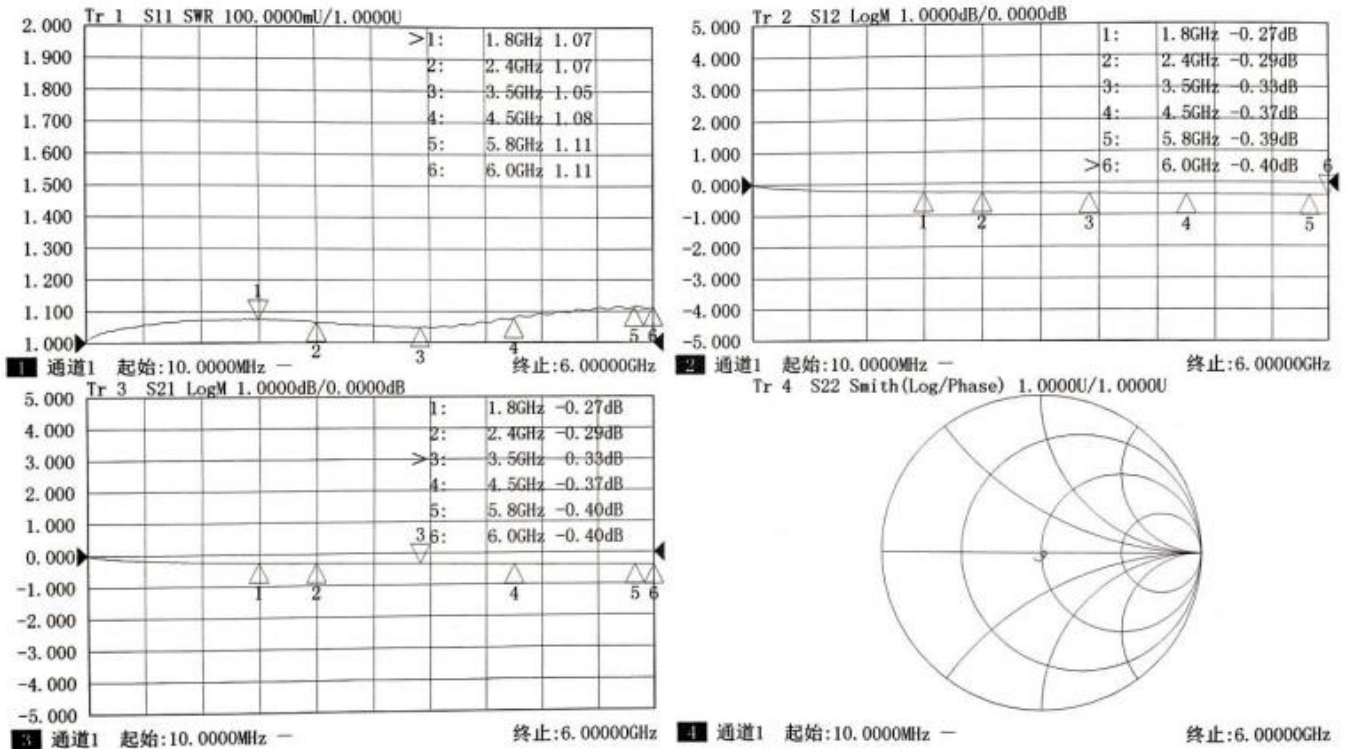
#### precision High frequency test probe

参数/Parameters	规格/Specifications
频率范围 Frequency Range	DC-8.5 GHz
插入损耗 Insertion loss	0.05dB max. (DC-3GHz)
	0.25dB max. (3GHz-6GHz)
	0.35dB max. (6GHz-8.5GHz)
电压驻波比 Voltage VSWR	1.08max. (DC-3GHz)
	1.1max. (3GHz-6GHz)
	1.15max. (6GHz-8.5GHz)
接触电阻 Contact Resistance	内导体之间 Between Inner conductors $\leq 3 \text{ m}\Omega$
	外导体之间 Between external conductor $\leq 2 \text{ m}\Omega$
	绝缘电阻 Insulation Resistance $\geq 1000 \text{ M}\Omega$
阻抗 Impedance	50 Ohms
材料 Material	插针 Pin: 铍青铜 镀金 Beryllium Bronze gold plating
	绝缘层 Insulating layer: 聚四氟乙烯 PTFE
	外壳 Shell: 黄铜 镀金 Brass gold plating
	接头 Connector: 铍青铜 镀金 Beryllium Bronze gold plating
外形尺寸 Outline Dimensions	24.8*16*6 (mm)
工作温度 Operation Temperature	-25°C ~ +327°C
耐用性 Durability	$\geq 10000$ 次



注: 尺寸(mm/[英寸]) , 一般公差(± 0.05)  
Note: Dimensions (mm / [inch]), General tolerance (±0.05)

## 测试报告/Test report:



## Probe 行程:

该产品 Probe 最大行程为 3.00mm, 建议实际使用行程控制在 2.0-2.5mm 之间。